

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKANISHI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 2002-075323	03-2002	Japan	Uemoto et al	H01M2/26
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NON-PATENT DOCUMENTS

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